



Session Title:	[WeG2] Frontier Metrology and Modeling IV
Session Date:	November 13 (Wed.), 2024
Session Time:	14:10-15:40
Session Room:	Room G (Meeting Room, 5F, Grand Josun Busan)
Session Chair:	Prof. Kumar Mohit (Ajou Univ., Korea)

[WeG2-1] [Invited]

14:10-14:40

Metrology and Inspection Challenges for High NA EUV

Dieter Van den Heuvel, Christophe Beral, Matteo Beggiato, Anne-Laure Charley, Gian Lorusso, Janusz Bogdanowicz, Hongcheon Yang (imec, Belgium)

[WeG2-2] [Invited]

14:40-15:10

Optical Metrology Development Trends in Today's Advanced Device Nodes

Nahee Park (KLA Corp., USA)

[WeG2-3] [Invited]

15:10-15:40

High NA Objective Lens Optical Design for Metrology & Inspection

Jun Ho Lee, Ji Yong Joo, Yu Bin Jo, Ji Hyun Park (Kongju Nat'l Univ., Korea), Hagyoung Kihm, Ho-Soon Yang (KRISS, Korea), and Oh-Hyung Kwon (Nextin, Korea)